Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10800397	FLESCH ET AL.
Examiner	Art Unit
Nano, Sargon N	2157

|--|--|

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Primary Yves Dalencourt	11/22/2008	SN

INTERFERENCE SEARCH		
Subclass	Date	Examiner
		_

U.S. Patent and Trademark Office Part of Paper No. : 20081122